

Title (en)

CIRCUIT AND PHOTO SENSOR OVERLAP FOR BACKSIDE ILLUMINATION IMAGE SENSOR

Title (de)

SCHALTUNGS- UND FOTOSENSORÜBERLAPPUNG FÜR EINEN RÜCKSEITENBELEUCHTUNGS-BILDSENSOR

Title (fr)

CHEVAUCHEMENT DE CIRCUIT ET DE PHOTODÉTECTEUR POUR UN DÉTECTEUR D IMAGES À RÉTROÉCLAIRAGE

Publication

EP 2253017 B1 20220330 (EN)

Application

EP 09708988 A 20090202

Priority

- US 2735608 P 20080208
- US 5347608 A 20080321
- US 2009032898 W 20090202

Abstract (en)

[origin: US2009200624A1] A backside illuminated ("BSI") imaging sensor pixel includes a photodiode region and pixel circuitry. The photodiode region is disposed within a semiconductor die for accumulating an image charge in response to light incident upon a backside of the BSI imaging sensor pixel. The pixel circuitry includes transistor pixel circuitry disposed within the semiconductor die between a frontside of the semiconductor die and the photodiode region. At least a portion of the pixel circuitry overlaps the photodiode region.

IPC 8 full level

H01L 27/146 (2006.01); **H04N 25/00** (2023.01)

CPC (source: EP US)

H01L 27/14603 (2013.01 - EP US); **H01L 27/1464** (2013.01 - EP US); **H01L 27/14641** (2013.01 - EP US); **H04N 25/772** (2023.01 - EP); **H04N 25/79** (2023.01 - EP US); **H01L 27/14627** (2013.01 - EP US)

Citation (examination)

- US 2006023109 A1 20060202 - MABUCHI KEIJI [JP], et al
- US 2006197007 A1 20060907 - IWABUCHI SHIN [JP], et al
- CHEN XU ET AL: "A new digital-pixel architecture for CMOS image sensor with pixel-level ADC and pulse width modulation using a 0.18 /spl mu/m CMOS technology", ELECTRON DEVICES AND SOLID-STATE CIRCUITS, 2003 IEEE CONFERENCE ON KOWLOON, HONG KONG DEC. 16-18, 2003, PISCATAWAY, NJ, USA,IEEE, 16 December 2003 (2003-12-16), pages 265 - 268, XP010695857, ISBN: 978-0-7803-7749-3, DOI: 10.1109/EDSSC.2003.1283528

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